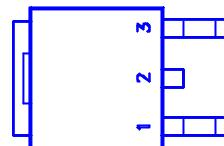
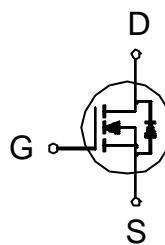


NIKO-SEM
**N-Channel Logic Level Enhancement
Mode Field Effect Transistor (Preliminary)**
**P2504BDG
TO-252 (DPAK)
Lead-Free**
PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
40V	25m	12A



1. GATE
2. DRAIN
3. SOURCE

ABSOLUTE MAXIMUM RATINGS ($T_C = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	40	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current	I_D	12	A
		10	
Pulsed Drain Current ¹	I_{DM}	45	A
Power Dissipation	P_D	41	
		32	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	$^\circ\text{C}$
Lead Temperature (1/16" from case for 10 sec.)	T_L	275	

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		3	$^\circ\text{C} / \text{W}$
Junction-to-Ambient	$R_{\theta JA}$		75	$^\circ\text{C} / \text{W}$

¹Pulse width limited by maximum junction temperature.²Duty cycle $\leq 1\%$ **ELECTRICAL CHARACTERISTICS ($T_C = 25^\circ\text{C}$, Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	40			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1	2.0	3.0	nA
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			± 250	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 32\text{V}, V_{GS} = 0\text{V}$			1	μA
		$V_{DS} = 30\text{V}, V_{GS} = 0\text{V}, T_C = 125^\circ\text{C}$			10	
On-State Drain Current ¹	$I_{D(\text{ON})}$	$V_{DS} = 10\text{V}, V_{GS} = 10\text{V}$	45			A
Drain-Source On-State Resistance ¹	$R_{DS(\text{ON})}$	$V_{GS} = 4.5\text{V}, I_D = 10\text{A}$		35	45	m
		$V_{GS} = 10\text{V}, I_D = 12\text{A}$		21	25	

NIKO-SEM

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Forward Transconductance ¹	g_{fs}	$V_{DS} = 10V, I_D = 12A$	18		S
DYNAMIC					
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 10V, f = 1MHz$	760		pF
Output Capacitance	C_{oss}		165		
Reverse Transfer Capacitance	C_{rss}		55		
Total Gate Charge ²	Q_g		16		
Gate-Source Charge ²	Q_{gs}	$V_{DS} = 0.5V_{(BR)DSS}, V_{GS} = 10V, I_D = 12A$	2.5		nC
Gate-Drain Charge ²	Q_{gd}		2.1		
Turn-On Delay Time ²	$t_{d(on)}$		2.1	4.2	
Rise Time ²	t_r		7.2	14	
Turn-Off Delay Time ²	$t_{d(off)}$	$I_D \approx 1A, V_{GS} = 10V, R_{GEN} = 6$	11.6	21.0	nS
Fall Time ²	t_f		3.5	7.2	
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_c = 25^\circ C$)					
Continuous Current	I_S			12	A
Pulsed Current ³	I_{SM}			40	
Forward Voltage ¹	V_{SD}	$I_S = I_S, V_{GS} = 0V$		1.2	V
Reverse Recovery Time	t_{rr}	$I_F = 5 A, dI_F/dt = 100A/\mu S$	14.5		nS
Reverse Recovery Charge	Q_{rr}		7.2		nC

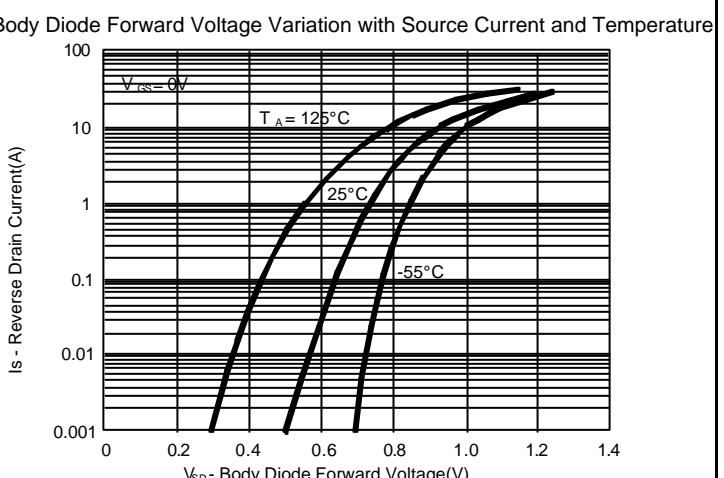
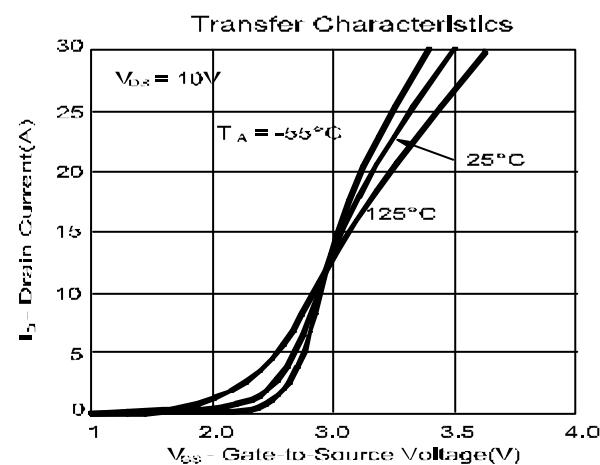
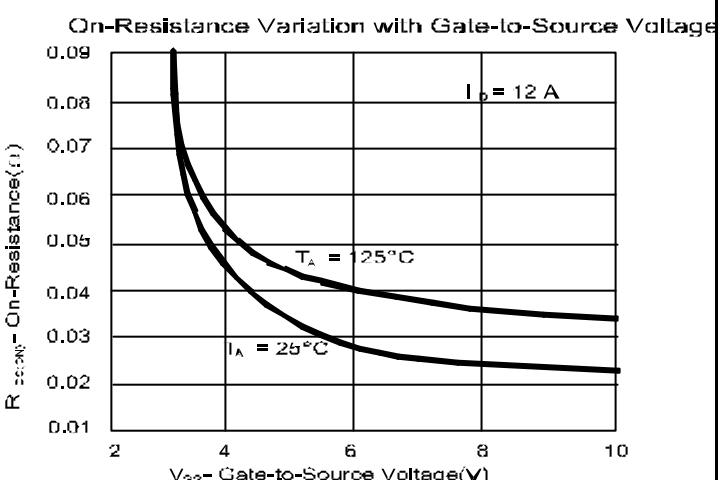
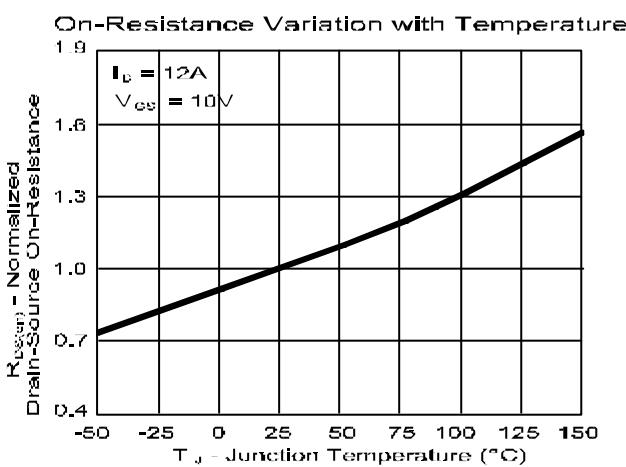
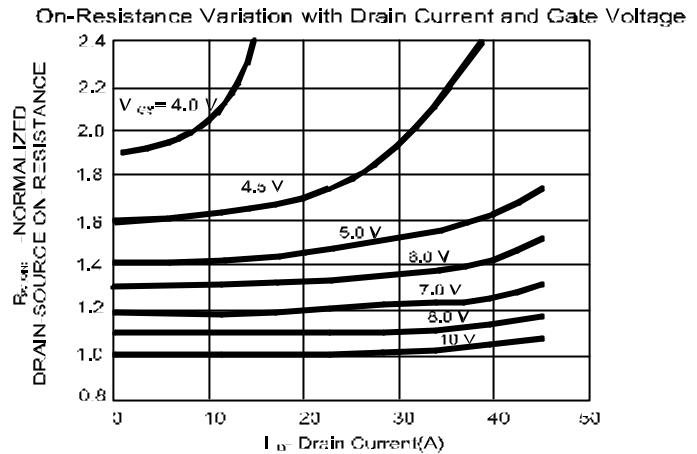
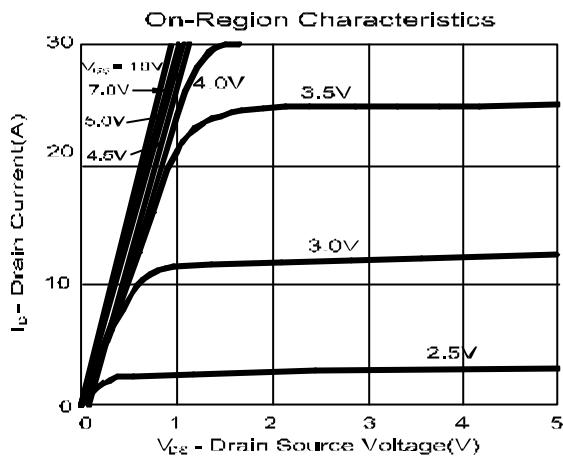
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.

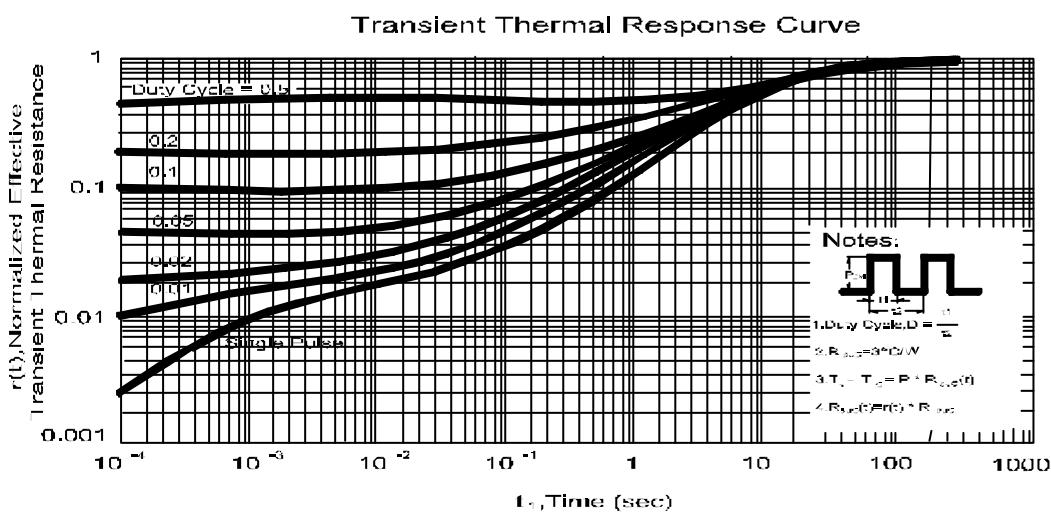
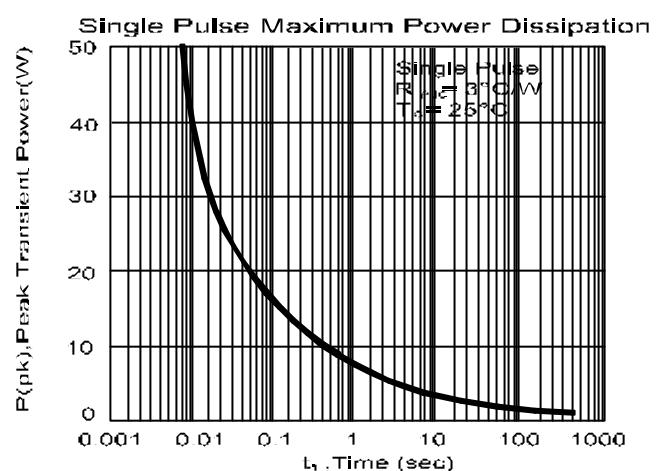
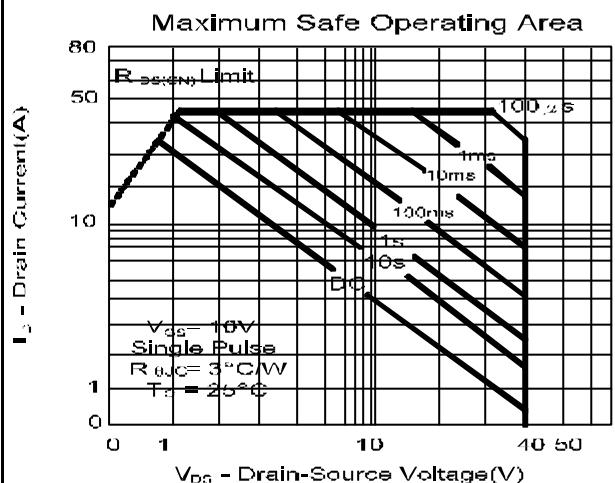
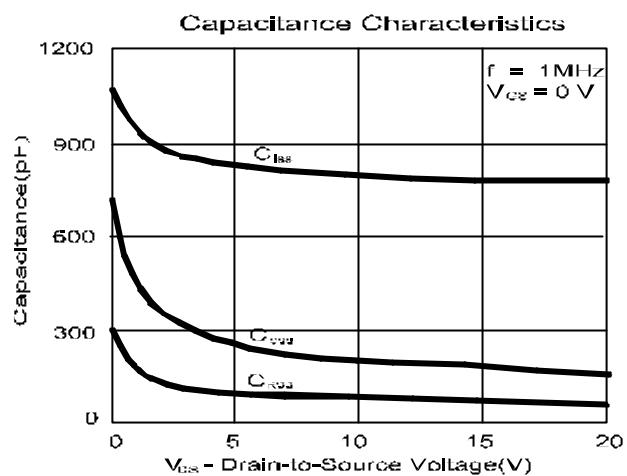
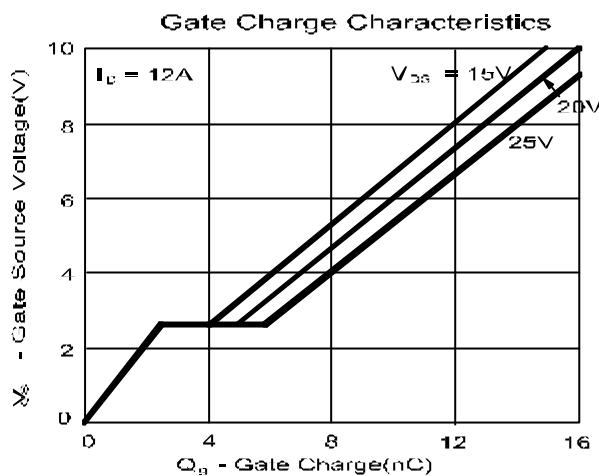
²Independent of operating temperature.

³Pulse width limited by maximum junction temperature.

REMARK: THE PRODUCT MARKED WITH "P2504BDG", DATE CODE or LOT #

Orders for parts with Lead-Free plating can be placed using the PXXXXXXG parts name.



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Mode Field Effect Transistor (Preliminary)****P2504BDG
TO-252 (DPAK)
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TO-252 (DPAK) MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	9.35		10.1	H		0.8	
B	2.2		2.4	I	6.4		6.6
C	0.48		0.6	J	5.2		5.4
D	0.89		1.5	K	0.6		1
E	0.45		0.6	L	0.64		0.9
F	0.03		0.23	M	4.4		4.6
G	6		6.2	N			

